Notice of References Cited Application/Control No. 10/531,491 Examiner Andrew C. Lee Applicant(s)/Patent Under Reexamination WARIS, HEIKKI Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
*	Α	US-2004/0117653	06-2004	Shapira et al.	713/201	
*	В	US-2002/0009066	01-2002	Shimizu et al.	370/338	
*	C	US-2002/0083046	06-2002	Yamauchi et al.	707/1	
*	D	US-2002/0041605	04-2002	Benussi et al.	370/467	
*	Е	US-2002/0161905	10-2002	Haverinen et al.	709/229	
*	F	US-6,999,437	02-2006	Krishnamurthi et al.	370/331	
*	G	US-2003/0224788	12-2003	Leung et al.	455/435.1	
*	Ι	US-6,915,345	07-2005	Tummala et al.	709/225	
*	-	US-7,065,067	06-2006	Song et al.	370/338	
*	J	US-2003/0091013	05-2003	Song et al.	370/338	
*	K	US-7,079,499	07-2006	Akhtar et al.	370/310	
*	L	US-2002/0018456	02-2002	Kakemizu et al.	370/338	
*	М	US-2004/0010712	01-2004	Hui et al.	713/201	

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	x	

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